

Search Notes**Application/Control No.**

10/538,715

Examiner

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**Applicant(s)/Patent under
Reexamination**

FARDEAU ET AL.

Art Unit

1651

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPG- pub;USPAT;USOCR:EPO;JPO;Derwe nt)	6/11/2007	TK
Inventor search (PALM)	6/11/2007	TK
BLAST search (NCBI)	6/11/2007	TK
updated search	2/11/2008	TK